Small Signal MOSFET 30 V, 0.56 A, Single N–Channel, SOT–23

Features

- Low Gate Voltage Threshold ($V_{GS(TH)}$) to Facilitate Drive Circuit Design
- Low Gate Charge for Fast Switching
- ESD Protected Gate
- SOT-23 Package Provides Excellent Thermal Performance
- Minimum Breakdown Voltage Rating of 30 V
- NVR Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC–Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

Applications

- Notebooks:
 - Level Shifters
 - Logic Switches
 - Low Side Load Switches
- Portable Applications

MAXIMUM RATINGS (T_J = 25° C unless otherwise noted)

Parame	Symbol	Value	Unit		
Drain-to-Source Voltage	V _{DSS}	30	V		
Gate-to-Source Voltage	V _{GS}	±20	V		
Continuous Drain	Steady	$T_A = 25^{\circ}C$	I _D	0.5	А
Current (Note 1)	State	$T_A = 85^{\circ}C$		0.37	
Power Dissipation (Note 1)	Stea	dy State	P _D	0.69	W
Continuous Drain	t < 10 s T _A = 25°C		Ι _D	0.56	А
Current (Note 1)		$T_A = 85^{\circ}C$		0.40	
Power Dissipation (Note 1)	t·	< 5 s	P _D	0.83	W
Pulsed Drain Current	t _p =	: 10 μs	I _{DM}	1.7	А
Operating Junction and S	Т _Ј , Та на	–55 to 150	°C		
	Tstg				
Source Current (Body Dio	۱ _S	1.0	А		
Lead Temperature for Sol (1/8" from case for 10 s)	ΤL	260	°C		

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Max	Unit
Junction-to-Ambient - Steady State (Note 1)	R_{\thetaJA}	180	°C/W
Junction-to-Ambient - t < 10 s (Note 1)	R_{\thetaJA}	150	
Junction-to-Ambient - Steady State (Note 2)	R_{\thetaJA}	300	

1. Surface-mounted on FR4 board using 1 in sq pad size

(Cu area = 1.127 in sq [1 oz] including traces).

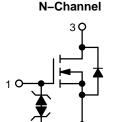
2. Surface-mounted on FR4 board using the minimum recommended pad size.

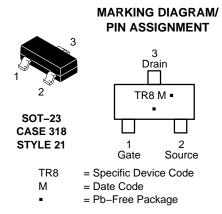


ON Semiconductor®

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V _{(BR)DSS}	R _{DS(on)} TYP	I _D MAX
30 V	1.0 Ω @ 4.0 V	0.56 A
	1.5 Ω @ 2.5 V	0.0071





(Note: Microdot may be in either location) *Date Code orientation and overbar may vary depending upon manufacturing location.

ORDERING INFORMATION

Device	Package	Shipping [†]
NTR4003NT1G	SOT–23 (Pb–Free)	3000 / Tape & Reel
NTR4003NT3G	SOT–23 (Pb–Free)	10,000 / Tape & Reel
NVR4003NT3G	SOT-23 (Pb-Free)	10,000 / Tape & Reel

⁺For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

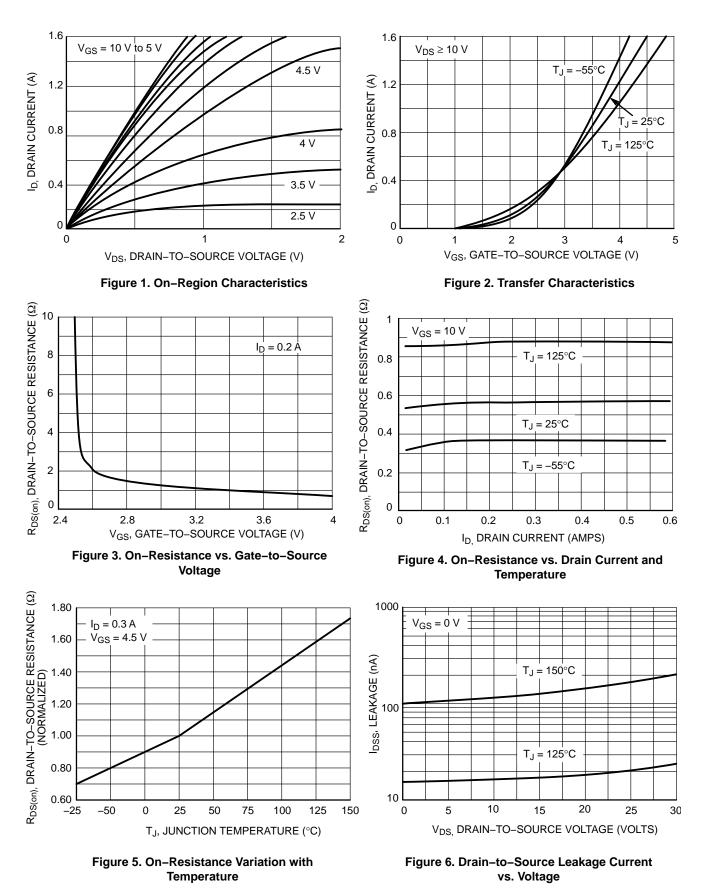
ELECTRICAL CHARACTERISTICS (T_J = 25° C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Units
OFF CHARACTERISTICS					•		
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 V, I_{D} = 100 \mu A$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				40		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V,$ $V_{DS} = 30 V$	T _J = 25°C			1.0	μΑ
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 10 V$				±1.0	μΑ
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D}$	= 250 μA	0.8		1.4	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				3.4		mV/°C
Drain-to-Source On Resistance	5	$V_{GS} = 4.0 \text{ V}, I_D = 10 \text{ mA}$			1.0	1.5	Ω
	R _{DS(on)}	$V_{GS} = 2.5 \text{ V}, I_D = 10 \text{ mA}$			1.5	2.0	
Forward Transconductance	9 _{FS}	$V_{DS} = 3.0 \text{ V}, I_{D} = 10 \text{ mA}$			0.33		S
CHARGES AND CAPACITANCES							-
Input Capacitance	C _{iss}	$V_{GS} = 0 V, f = 1.0 MHz,$ $V_{DS} = 5.0 V$			21	42	pF
Output Capacitance	C _{oss}				19.7	40	
Reverse Transfer Capacitance	C _{rss}	. 53			8.1	16	1
Total Gate Charge	Q _{G(TOT)}				1.15		nC
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 5.0 V, V	ns = 24 V,		0.15		
Gate-to-Source Gate Charge	Q _{GS}	$V_{GS} = 5.0 \text{ V}, \text{ V}_{I}$ $I_{D} = 0.$	1 A		0.32		
Gate-to-Drain Charge	Q _{GD}				0.23		1
SWITCHING CHARACTERISTICS (Note	e 4)						
Turn-On Delay Time	t _{d(on)}				16.7		
Rise Time	tr	V_{GS} = 4.5 V, V_{DD} = 5.0 V, I _D = 0.1 A, R _G = 50 Ω			47.9		ns
Turn–Off Delay Time	t _{d(off)}				65.1	1	
Fall Time	t _f				64.2		
SOURCE-DRAIN DIODE CHARACTER	ISTICS						
Forward Diode Voltage	V _{SD}	$V_{GS} = 0 V,$	$T_J = 25^{\circ}C$		0.65	0.7	V
	$I_{\rm S} = 10 \text{ mÅ}$ $T_{\rm J} = 125^{\circ}\text{C}$		T _J = 125°C		0.45		1

Reverse Recovery Time $\begin{array}{rl} V_{GS} &=& 0 \ V, \ dI_S/dt = 8A/\mu s, \\ I_S &=& 10 \ mA \end{array}$ 14 t_{RR} ns

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 3. Pulse Test: pulse width $\leq 300 \ \mu$ s, duty cycle $\leq 2\%$. 4. Switching characteristics are independent of operating junction temperatures.

TYPICAL PERFORMANCE CURVES (T_J = 25° C unless otherwise noted)



TYPICAL PERFORMANCE CURVES ($T_J = 25^{\circ}C$ unless otherwise noted)

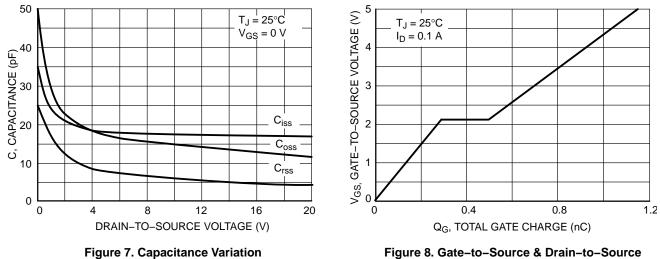


Figure 8. Gate-to-Source & Drain-to-Source Voltage vs. Total Charge

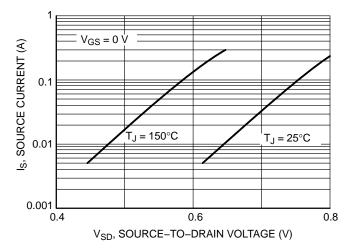
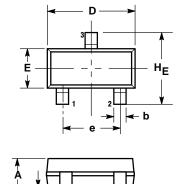


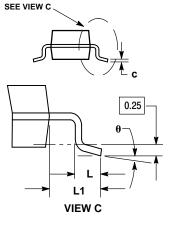
Figure 9. Diode Forward Voltage vs. Current

PACKAGE DIMENSIONS

SOT-23 (TO-236) CASE 318-08 ISSUE AP

NOTES:





DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
CONTROLLING DIMENSION: INCH.
MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH

MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL.

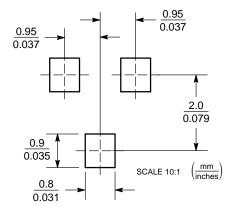
A. DIMENSIONS OF AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

	MILLIMETERS			INCHES					
DIM	MIN	NOM	MAX	MIN	MIN NOM I				
Α	0.89	1.00	1.11	0.035	0.040	0.044			
A1	0.01	0.06	0.10	0.001	0.002	0.004			
b	0.37	0.44	0.50	0.015	0.018	0.020			
С	0.09	0.13	0.18	0.003	0.005	0.007			
D	2.80	2.90	3.04	0.110	0.114	0.120			
Е	1.20	1.30	1.40	0.047	0.051	0.055			
е	1.78	1.90	2.04	0.070	0.075	0.081			
L	0.10	0.20	0.30	0.004	0.008	0.012			
L1	0.35	0.54	0.69	0.014	0.021	0.029			
HE	2.10	2.40	2.64	0.083	0.094	0.104			
θ	0°		10°	0°		10°			



PIN 1. GATE 2. SOURCE 3. DRAIN

SOLDERING FOOTPRINT*



*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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